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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

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Details	
Product Status	Active
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I ² C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	48
Program Memory Size	64KB (64K × 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 12x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LFQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f101leafb-50

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1	P00 to P07, P10 to P17, P30 to P37, P40 to P47, P50 to P57, P64 to P67, P70 to P77, P80 to P87, P90 to P97, P100 to P106, P110 to P117, P120, P125 to P127, P140 to P147		0.8EVDD0		EVDDO	V
	VIH2	P01, P03, P04, P10, P11, P13 to P17, P43, P44, P53 to P55,	TTL input buffer $4.0 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$	2.2		EVDDO	V
		P80, P81, P142, P143	TTL input buffer $3.3 \text{ V} \leq \text{EV}_{\text{DD0}} < 4.0 \text{ V}$	2.0		EVDDO	V
			TTL input buffer $1.6 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}$	1.5		EVDDO	V
	VIH3	P20 to P27, P150 to P156	0.7V _{DD}		VDD	V	
	VIH4	P60 to P63	0.7EVDD0		6.0	V	
	VIH5	P121 to P124, P137, EXCLK, EXCL	0.8Vdd		VDD	V	
Input voltage, low	VIL1	P00 to P07, P10 to P17, P30 to P37, P40 to P47, P50 to P57, P64 to P67, P70 to P77, P80 to P87, P90 to P97, P100 to P106, P110 to P117, P120, P125 to P127, P140 to P147		0		0.2EV _{DD0}	V
	VIL2	P01, P03, P04, P10, P11, P13 to P17, P43, P44, P53 to P55,	TTL input buffer 4.0 V \leq EV _{DD0} \leq 5.5 V	0		0.8	V
		P80, P81, P142, P143	TTL input buffer 3.3 V \leq EV _{DD0} $<$ 4.0 V	0		0.5	V
			TTL input buffer 1.6 V ≤ EV _{DD0} < 3.3 V	0		0.32	V
	VIL3	P20 to P27, P150 to P156	0		0.3Vdd	V	
	VIL4	P60 to P63		0		0.3EVDD0	V
	VIL5	P121 to P124, P137, EXCLK, EXCL	0		0.2VDD	V	

- Caution The maximum value of V_{IH} of pins P00, P02 to P04, P10 to P15, P17, P43 to P45, P50, P52 to P55, P71, P74, P80 to P82, P96, and P142 to P144 is EV_{DD0}, even in the N-ch open-drain mode.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



- **Notes 1.** Total current flowing into V_{DD} and EV_{DD0}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD}, EV_{DD0} or V_{SS}, EV_{SS0}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
 - 2. When high-speed on-chip oscillator and subsystem clock are stopped.
 - 3. When high-speed system clock and subsystem clock are stopped.
 - 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
 - 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.7 V \leq V_DD \leq 5.5 V@1 MHz to 32 MHz

2.4 V \leq V_{DD} \leq 5.5 V@1 MHz to 16 MHz

LS (low-speed main) mode: $1.8~V \leq V_{\text{DD}} \leq 5.5~V @\,1$ MHz to 8 MHz

LV (low-voltage main) mode: 1.6 V \leq V_DD \leq 5.5 V@1 MHz to 4 MHz

- **Remarks 1.** fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - **3.** fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation, temperature condition of the TYP. value is $T_A = 25^{\circ}C$



(3) 128-pin products, and flash ROM: 384 to 512 KB of 44- to 100-pin products

$(TA = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V}) (1/2)$

Parameter	Symbol			Conditions	-		MIN.	TYP.	MAX.	Unit
Supply	IDD1	Operating	HS (high-	$f_{IH} = 32 \text{ MHz}^{Note 3}$	Basic	V _{DD} = 5.0 V		2.6		mA
current Note 1		mode	speed main) mode ^{Note 5}		operation	$V_{DD} = 3.0 V$		2.6		mA
					Normal	$V_{DD} = 5.0 V$		6.1	9.5	mA
					operation	$V_{DD} = 3.0 V$		6.1	9.5	mA
				$f_{IH} = 24 \text{ MHz}^{Note 3}$	Normal	$V_{DD} = 5.0 V$		4.8	7.4	mA
					operation	$V_{DD} = 3.0 V$		4.8	7.4	mA
				$f_{IH} = 16 \ MHz^{Note \ 3}$	Normal	$V_{DD} = 5.0 V$		3.5	5.3	mA
					operation	V _{DD} = 3.0 V		3.5	5.3	mA
			LS (low-	$f_{IH} = 8 \text{ MHz}^{Note 3}$	Normal	$V_{DD} = 3.0 V$		1.5	2.3	mA
			speed main) mode ^{Note 5}		operation	$V_{DD} = 2.0 V$		1.5	2.3	mA
			LV (low-	$f_{IH} = 4 \text{ MHz}^{Note 3}$	Normal	$V_{DD} = 3.0 V$		1.5	2.0	mA
			voltage main) mode		operation	V _{DD} = 2.0 V		1.5	2.0	mA
			HS (high- speed main) mode ^{Note 5}	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		3.9	6.1	mA
				V _{DD} = 5.0 V	operation	Resonator connection		4.1	6.3	mA
				f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		3.9	6.1	mA
				$V_{DD} = 3.0 V$	operation	Resonator connection		4.1	6.3	mA
				$f_{MX} = 10 \text{ MHz}^{Note 2},$	Normal	Square wave input		2.5	3.7	mA
				$V_{DD} = 5.0 V$	operation	Resonator connection		2.5	3.7	mA
			LS (low- speed main) mode ^{Note 5}	$f_{MX} = 10 \text{ MHz}^{Note 2},$		Square wave input		2.5	3.7	mA
				$V_{DD} = 3.0 V$	operation	Resonator connection		2.5	3.7	mA
				$f_{MX} = 8 \text{ MHz}^{Note 2},$	operation	Square wave input		1.4	2.2	mA
				V _{DD} = 3.0 V		Resonator connection		1.4	2.2	mA
				$f_{MX} = 8 \text{ MHz}^{Note 2},$	Normal	Square wave input		1.4	2.2	mA
				$V_{DD} = 2.0 V$	operation	Resonator connection		1.4	2.2	mA
			Subsystem	fsub = 32.768 kHz	Normal	Square wave input		5.4	6.5	μA
			clock operation	$T_A = -40^{\circ}C$	operation	Resonator connection		5.5	6.6	μA
				fsub = 32.768 kHz	Normal	Square wave input		5.5	6.5	μA
				$T_A = +25^{\circ}C$	operation	Resonator connection		5.6	6.6	μA
				fsub = 32.768 kHz	Normal	Square wave input		5.6	9.4	μA
				$T_{A} = +50^{\circ}C$	operation	Resonator connection		5.7	9.5	μA
				fsuв = 32.768 kHz	Normal	Square wave input		5.9	12.0	μA
				Note 4 $T_A = +70^{\circ}C$	operation	Resonator connection		6.0	12.1	μA
				fsuв = 32.768 kHz	Normal	Square wave input		6.6	16.3	μA
				Note 4 $T_A = +85^{\circ}C$	operation	Resonator connection		6.7	16.4	μA

(Notes and Remarks are listed on the next page.)



Parameter	Symbol	Conditions		HS (high main)	•	LS (low main)	r-speed Mode	LV (low-voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tксүı	tксү1 ≥ 4/fclk	$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$	125		500		1000		ns
			$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$	250		500		1000		ns
			$\begin{array}{l} 1.8 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$	500		500		1000		ns
			$\begin{array}{l} 1.7 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$	1000		1000		1000		ns
			$\begin{array}{l} 1.6 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$	—		1000		1000		ns
SCKp high-/low-level width	ow-level tkH1, $4.0 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$ tkL1		5.5 V	tксү1/2 – 12		tксү1/2 – 50		tксү1/2 – 50		ns
		$2.7~V \leq EV_{\text{DD0}} \leq 5.5~V$		tксү1/2 – 18		tксү1/2 – 50		tксү1/2 – 50		ns
		$2.4~V \leq EV_{\text{DD0}} \leq 5.5~V$		tксү1/2 – 38		tксү1/2 – 50		tксү1/2 – 50		ns
		$1.8 \text{ V} \leq \text{EV}_{\text{DI}}$	$500 \leq 5.5 \text{ V}$	tксү1/2 – 50		tксү1/2 – 50		tксү1/2 – 50		ns
		$1.7 \text{ V} \leq \text{EV}_{\text{DI}}$	$100 \leq 5.5 \text{ V}$	tксү1/2 – 100		tксү1/2 – 100		tксү1/2 – 100		ns
		$1.6 V \le EV_{DI}$	$500 \leq 5.5 \text{ V}$	—		tксү1/2 – 100		tксү1/2 – 100		ns
SIp setup time	tsik1	$4.0 V \le EV_{DI}$	$100 \leq 5.5 \text{ V}$	44		110		110		ns
(to SCKp↑) Note 1		$2.7 \text{ V} \leq \text{EV}_{\text{DI}}$	$00 \leq 5.5 \text{ V}$	44		110		110		ns
		$2.4 V \le EV_{DI}$	$0.0 \leq 5.5 \text{ V}$	75		110		110		ns
		$1.8 V \le EV_{DI}$	$0.0 \leq 5.5 \text{ V}$	110		110		110		ns
		$1.7 \text{ V} \leq \text{EV}_{\text{DI}}$	$0.0 \leq 5.5 \text{ V}$	220		220		220		ns
		$1.6 \text{ V} \leq \text{EV}_{\text{DI}}$	5.5 V			220		220		ns
SIp hold time	tksi1	$1.7 \text{ V} \leq \text{EV}_{\text{DI}}$	5.5 V	19		19		19		ns
(from SCKp \uparrow) Note 2		$1.6 \text{ V} \leq \text{EV}_{\text{DI}}$	5.5 V	—		19		19		ns
Delay time from SCKp↓ to SOp	tkso1	$\begin{array}{l} 1.7 \ V \leq EV_{DI} \\ C = 30 \ pF^{\text{Note}} \end{array}$			25		25		25	ns
output Note 3		$1.6 V \le EV_{DI}$ C = 30 pF ^{Note}			_		25		25	ns

(3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output) ($T_4 = -40$ to $+85^{\circ}$ C, 1.6 V \leq EVppa = EVpp1 \leq Vpp \leq 5.5 V, Vss = EVssa = EVssa = 0 V)

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to $SCKp\downarrow$ " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 4. C is the load capacitance of the SCKp and SOp output lines.
- Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Parameter	Symbo I		Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		LV (low-voltage main) Mode	
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↑) ^{Note 1}	tsik2	2.7 V ≤ E	$EV_{DD0} \leq 5.5 V$	1/fмск+2 0		1/fмск+30		1/fмск+30		ns
		1.8 V ≤ E	$EV_{DD0} \leq 5.5 \text{ V}$	1/fмск+3 0		1/fмск+30		1/fмск+30		ns
		1.7 V ≤ E	$EV_{DD0} \leq 5.5 \text{ V}$	1/fмск+4 0		1/fмск+40		1/fмск+40		ns
		1.6 V ≤	$EV_{DD0} \leq 5.5 V$			1/fмск+40		1/fмск+40		ns
SIp hold time (from SCKp↑)	_	$1.8~V \leq EV_{\text{DD0}} \leq 5.5~V$		1/fмск+3 1		1/fмск+31		1/fмск+31		ns
Note 2		1.7 V ≤ E	$EV_{DD0} \leq 5.5 \text{ V}$	1/fмск+ 250		1/fмск+ 250		1/fмск+ 250		ns
		1.6 V ≤	$EV_{DD0} \leq 5.5 V$	—		1/fмск+ 250		1/fмск+ 250		ns
Delay time from SCKp↓ to	tkso2	C = 30 pF ^{Note 4}	$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$		2/f _{мск+} 44		2/f _{мск+} 110		2/f _{мск+} 110	ns
SOp output Note 3			$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$		2/fмск+ 75		2/fмск+ 110		2/fмск+ 110	ns
			$\begin{array}{l} 1.8 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$		2/fмск+ 110		2/fмск+ 110		2/fмск+ 110	ns
			$\begin{array}{l} 1.7 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$		2/fмск+ 220		2/fмск+ 220		2/fмск+ 220	ns
			$\begin{array}{l} 1.6 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$		_		2/fмск+ 220		2/fмск+ 220	ns

(4)	During communication at same potential (CSI mode) (slave mode, SCKp external clock input) (2/2)
	$(T_A = -40 \text{ to } \pm 85^{\circ}\text{C} = 1.6 \text{ V} \leq \text{EV}_{DD0} = \text{EV}_{DD1} \leq \text{V}_{DD1} \leq 5.5 \text{ V}_{D0} \text{ V}_{SS} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0.0 \text{ V}_{D1}$

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 4. C is the load capacitance of the SOp output lines.
 - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. p: CSI number (p = 00, 01, 10, 11, 20, 21, 30, 31), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM number (g = 0, 1, 4, 5, 8, 14)

fMCK: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))



(7)	Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCKp internal clock output,
	corresponding CSI00 only) (2/2)

Parameter	Symbol	Conditions	、 U	h-speed Mode	LS (low-speed main) Mode			-voltage Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↓) ^{Note 2}	tsikı	$\label{eq:states} \begin{split} 4.0 \ V &\leq EV_{\text{DD0}} \leq 5.5 \ V, \\ 2.7 \ V &\leq V_b \leq 4.0 \ V, \end{split}$	23		110		110		ns
		$C_{b}=20 \text{ pF}, \text{R}_{b}=1.4 \text{k}\Omega$							
		$\label{eq:V_def} \begin{split} 2.7 \ V &\leq EV_{\text{DD0}} < 4.0 \ V, \\ 2.3 \ V &\leq V_{\text{b}} \leq 2.7 \ V, \end{split}$	33		110		110		ns
		$C_{b}=20 \text{ pF}, \text{R}_{b}=2.7 \text{k}\Omega$							
SIp hold time (from SCKp↓) ^{№te 2}	tksii	$\begin{array}{l} 4.0 \; V \leq E V_{\text{DD0}} \leq 5.5 \; V, \\ 2.7 \; V \leq V_{\text{b}} \leq 4.0 \; V, \end{array}$	10		10		10		ns
		$C_{b}=20 \text{ pF}, \text{R}_{b}=1.4 \text{k}\Omega$							
		$\label{eq:V_def} \begin{split} 2.7 \ V &\leq E V_{\text{DD0}} < 4.0 \ V, \\ 2.3 \ V &\leq V_{\text{b}} \leq 2.7 \ V, \end{split}$	10		10		10		ns
		$C_{b}=20 \text{ pF}, \text{R}_{b}=2.7 \text{k}\Omega$							
Delay time from SCKp↑ to	tkso1	$\label{eq:V_def} \begin{split} 4.0 \ V &\leq EV_{\text{DD0}} \leq 5.5 \ V, \\ 2.7 \ V &\leq V_b \leq 4.0 \ V, \end{split}$		10		10		10	ns
SOp output Note 2		$C_{b}=20 \text{ pF}, \text{R}_{b}=1.4 \text{k}\Omega$							
		$\label{eq:V_def} \begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \end{array}$		10		10		10	ns
		$C_{b}=20 \text{ pF}, \text{R}_{b}=2.7 \text{k}\Omega$							

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

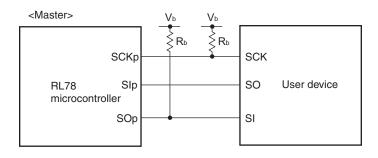
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance (When 20- to 52-pin products)/EV_{DD} tolerance (When 64- to 128-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** R_b[Ω]:Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0),
 g: PIM and POM number (g = 1)
 - 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

- n: Channel number (mn = 00))
- 4. This value is valid only when CSI00's peripheral I/O redirect function is not used.



CSI mode connection diagram (during communication at different potential)



- **Remarks 1.** R_b[Ω]:Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 01, 10, 20, 30, 31), m: Unit number, n: Channel number (mn = 00, 01, 02, 10, 12, 13), g: PIM and POM number (g = 0, 1, 4, 5, 8, 14)
 - **3.** fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).
 m: Unit number, n: Channel number (mn = 00))
 - **4.** CSI01 of 48-, 52-, 64-pin products, and CSI11 and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.



(9) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input)

Parameter	Symbol		<u>≤ Vod ≤ 5.5 V, Vss =</u> nditions	HS (speed	high- main) de	LS (low			-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time ^{Note 1}		$4.0 V \le EV_{DD0} \le 5.5 V$, $2.7 V \le V_b \le 4.0 V$	24 MHz < fмск	14/ fмск				_		ns
			20 MHz < fмск ≤ 24 MHz	12/ fмск		_		—		ns
			8 MHz < fмск ≤ 20 MHz	10/ fмск						ns
			4 MHz < fмск ≤ 8 MHz	8/fмск		16/ fмск				ns
		fмск ≤4 MHz	6/f мск		10/ fмск		10/ fмск		ns	
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V	24 MHz < fмск	20/ fмск				_		ns
			20 MHz < fмск ≤ 24 MHz	16/ fмск				—		ns
			16 MHz < fмск ≤ 20 MHz	14/ fмск				_		ns
			8 MHz < fмск ≤ 16 MHz	12/ fмск						ns
			4 MHz < fмск ≤ 8 MHz	8/fмск		16/ fмск				ns
			fмск ≤4 MHz	6/fмск		10/ fмск		10/ fмск		ns
		$\begin{split} & 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \\ & 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note}} \end{split}$	24 MHz < fмск	48/ fмск		_		—		ns
		2	20 MHz < fмск ≤ 24 MHz	36/ fмск		_				ns
			16 MHz < fмск ≤ 20 MHz	32/ fмск		—		_		ns
			8 MHz < fмск ≤ 16 MHz	26/ fмск		_		_		ns
			4 MHz < fмск ≤ 8 MHz	16/ fмск		16/ fмск		_		ns
			fмск ≤4 MHz	10/ fмск		10/ fмск		10/ fмск		ns

(Notes and Caution are listed on the next page, and Remarks are listed on the page after the next page.)



(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AV_{REFM}/ANI1 (ADREFM = 1), target pin : ANI0, ANI2 to ANI14, ANI16 to ANI26

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 1.6 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}, \text{Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{V}_{BGR}^{\text{Note 3}}, \text{ Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V}^{\text{Note 4}}, \text{HS (high-speed main) mode}$

Parameter	Symbol	Cond	MIN.	TYP.	MAX.	Unit	
Resolution	RES				8		bit
Conversion time	t CONV	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	8-bit resolution	$2.4~V \leq V \text{DD} \leq 5.5~V$			±0.60	%FSR
Integral linearity error ^{Note 1}	ILE	8-bit resolution	$2.4~V \leq V \text{DD} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±1.0	LSB
Analog input voltage	VAIN			0		$V_{\text{BGR}}{}^{\text{Note 3}}$	V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

4. When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error: Add $\pm 0.35\%$ FSR to the MAX. value when reference voltage (–) = AV_{REFM}. Integral linearity error: Add ± 0.5 LSB to the MAX. value when reference voltage (–) = AV_{REFM}. Differential linearity error: Add ± 0.2 LSB to the MAX. value when reference voltage (–) = AV_{REFM}.



Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1	P00 to P07, P10 to P17, P30 to P37, P40 to P47, P50 to P57, P64 to P67, P70 to P77, P80 to P87, P90 to P97, P100 to P106, P110 to P117, P120, P125 to P127, P140 to P147	·	0.8EV _{DD0}		EVDDO	V
	VIH2	P01, P03, P04, P10, P11, P13 to P17, P43, P44, P53 to P55,	TTL input buffer $4.0 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$	2.2		EVDD0	V
		P80, P81, P142, P143	TTL input buffer $3.3 \text{ V} \leq \text{EV}_{\text{DD0}} < 4.0 \text{ V}$	2.0		EVDD0	V
			TTL input buffer $2.4 \text{ V} \leq EV_{\text{DD0}} < 3.3 \text{ V}$			EVDDO	V
	VIH3	P20 to P27, P150 to P156	0.7V _{DD}		VDD	V	
	VIH4	P60 to P63	0.7EVDD0		6.0	V	
	VIH5	P121 to P124, P137, EXCLK, EXCL	0.8Vdd		VDD	V	
Input voltage, low	VIL1	P00 to P07, P10 to P17, P30 to P37, P40 to P47, P50 to P57, P64 to P67, P70 to P77, P80 to P87, P90 to P97, P100 to P106, P110 to P117, P120, P125 to P127, P140 to P147		0		0.2EV _{DD0}	V
	VIL2	P01, P03, P04, P10, P11, P13 to P17, P43, P44, P53 to P55,	TTL input buffer 4.0 V \leq EV _{DD0} \leq 5.5 V	0		0.8	V
		P80, P81, P142, P143	TTL input buffer 3.3 V ≤ EV _{DD0} < 4.0 V	0		0.5	V
			TTL input buffer 2.4 V \leq EV _{DD0} $<$ 3.3 V	0		0.32	V
	VIL3	P20 to P27, P150 to P156		0		0.3VDD	V
	VIL4	P60 to P63		0		0.3EVDD0	V
	VIL5	P121 to P124, P137, EXCLK, EXCLK	(S, RESET	0		0.2VDD	V

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$ (3/5)

- Caution The maximum value of V_{IH} of pins P00, P02 to P04, P10 to P15, P17, P43 to P45, P50, P52 to P55, P71, P74, P80 to P82, P96, and P142 to P144 is EV_{DD0}, even in the N-ch open-drain mode.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	V _{OH1}	P00 to P07, P10 to P17, P30 to P37, P40 to P47, P50 to P57, P64	$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -3.0 \ \text{mA} \end{array}$	EV _{DD0} - 0.7			V
		DOD to DOZ D100 to D100 D110 to	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 5.5 \text{ V},$ Іон1 = -2.0 mA	EV _{DD0} - 0.6			V
		P117, P120, P125 to P127, P130, P140 to P147	$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -1.5 \ mA \end{array}$	EV _{DD0} - 0.5			V
	Vон2	P20 to P27, P150 to P156	$\begin{array}{l} \text{2.4 V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}, \\ \text{I}_{\text{OH2}} = -100 \ \mu \text{ A} \end{array}$	Vdd - 0.5			۷
Output voltage, low	Vol1	P37, P40 to P47, P50 to P57, P64	$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 8.5 \ mA \end{array} \end{array} \label{eq:DD1}$			0.7	V
	to P67, P70 to P77, P80 to P87, P90 to P97, P100 to P106, P110 to	$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 3.0 \ mA \end{array} \end{array} \label{eq:DD1}$			0.6	V	
		P140 to P147	$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 1.5 \ mA \end{array} \end{array} \label{eq:DD1}$			0.4	V
			$eq:local_$			0.4	V
	Vol2	P20 to P27, P150 to P156	$\begin{array}{l} \text{2.4 V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}, \\ \text{Iol2} = 400 \ \mu \text{ A} \end{array}$			0.4	V
	Vol3		$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ I_{\text{OL3}} = 15.0 \ mA \end{array} \end{array}$			2.0	V
		$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ I_{\text{OL3}} = 5.0 \ mA \end{array}$			0.4	V	
		$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ I_{\text{OL3}} = 3.0 \ mA \end{array} \end{array} \label{eq:DD1}$			0.4	V	
			$\label{eq:loss_states} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \\ \\ I_{\text{OL3}} = 2.0 \ mA \end{array}$			0.4	V

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$ (4/5)

Caution P00, P02 to P04, P10 to P15, P17, P43 to P45, P50, P52 to P55, P71, P74, P80 to P82, P96, and P142 to P144 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Parameter	Symbol	Con	ditions	HS (high-speed ma	ain) Mode	Unit
				MIN.	MAX.	
SCKp cycle time Note 5	t ксү2	$4.0~V \leq EV_{\text{DD0}} \leq 5.5$	20 MHz < fмск	16/ fмск		ns
		V	fмск \leq 20 MHz	12/fмск		ns
		$2.7~V \leq EV_{\text{DD0}} \leq 5.5$	16 MHz < fмск	16/ fмск		ns
		V	fмск \leq 16 MHz	12/fмск		ns
		$2.4~V \leq EV_{\text{DD0}} \leq 5.5~V$,	16/fмск		ns
				12/fмск and 1000		ns
SCKp high-/low-level	tкн2, tк∟2	$4.0~V \leq EV_{\text{DD0}} \leq 5.5$	V	tксү2/2 – 14		ns
width		$2.7~V \leq EV_{\text{DD0}} \leq 5.5~V$		tксү2/2 – 16		ns
		$2.4~V \leq EV_{\text{DD0}} \leq 5.5$	V	tксү2/ 2 – 36		ns
SIp setup time	tsik2	$2.7~V \leq EV_{\text{DD0}} \leq 5.5$	V	1/fмск+40		ns
(to SCKp↑) ^{Note 1}		$2.4~V \leq EV_{\text{DD0}} \leq 5.5$	V	1/fмск+60		ns
SIp hold time (from SCKp↑) ^{№te 2}	tksi2	$2.4~V \leq EV_{\text{DD0}} \leq 5.5$	V	1/fмск+62		ns
Delay time from SCKp↓ to SOp output	tkso2	C = 30 pF Note 4	$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$		2/fмск+66	ns
Note 3			$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} \leq 5.5 \\ V \end{array}$		2/fмск+113	ns

(3)	During communication at same potential (CSI mode) (slave mode, SCKp external clock input)
	$(T_A = -40 \text{ to } \pm 105^{\circ}\text{C} 24 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD} \le 55 \text{ V}_{D0} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0.\text{ V}_{D1}$

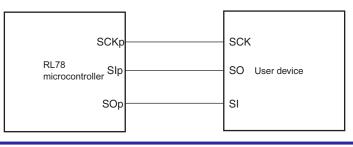
- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 4. C is the load capacitance of the SOp output lines.
 - 5. Transfer rate in the SNOOZE mode : MAX. 1 Mbps

Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** p: CSI number (p = 00, 01, 10, 11, 20, 21, 30, 31), m: Unit number (m = 0, 1), p: Changel number (n = 0, ta 2) an EMA number (n = 0, 1, 4, 5, 0, 14)
 - n: Channel number (n = 0 to 3), g: PIM number (g = 0, 1, 4, 5, 8, 14)
 - 2. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

CSI mode connection diagram (during communication at same potential)





Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
SCLr clock frequency	fscL	$2.7~V \leq EV_{\text{DD0}} \leq 5.5~V,$		400 Note1	kHz
		$C_b = 50 \text{ pF}, \text{ R}_b = 2.7 \text{ k}\Omega$			
		$2.4~V \leq EV_{\text{DD0}} \leq 5.5~V,$		100 Note1	kHz
		$C_b = 100 \text{ pF}, \text{ R}_b = 3 \text{k}\Omega$			
Hold time when SCLr = "L"	t∟ow	$2.7~V \leq EV_{\text{DD0}} \leq 5.5~V,$	1200		ns
		$C_b = 50 \text{ pF}, \text{ R}_b = 2.7 \text{ k}\Omega$			
		$2.4~V \leq EV_{\text{DD0}} \leq 5.5~V,$	4600		ns
		$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$			
Hold time when SCLr = "H"	tніgн	$2.7~V \leq EV_{\text{DD0}} \leq 5.5~V,$	1200		ns
		$C_b = 50 \text{ pF}, \text{R}_b = 2.7 \text{ k}\Omega$			
		$2.4~V \leq EV_{\text{DD0}} \leq 5.5~V,$	4600		ns
		$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$			
Data setup time (reception)	tsu:dat	$2.7~V \leq EV_{\text{DD0}} \leq 5.5~V,$	1/fмск + 220		ns
		$C_b = 50 \text{ pF}, \text{ R}_b = 2.7 \text{ k}\Omega$	Note2		
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V,$	1/fмск + 580		ns
		$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$	Note2		
Data hold time (transmission)	thd:dat	$2.7~V \leq EV_{\text{DD0}} \leq 5.5~V,$	0	770	ns
		C_b = 50 pF, R_b = 2.7 k Ω			
		$2.4~V \leq EV_{\text{DD0}} \leq 5.5~V,$	0	1420	ns
		$C_b = 100 \text{ pF}, \text{ R}_b = 3 \text{k}\Omega$			

(4) During communication at same potential (simplified l²C mode) (T_A = -40 to +105°C, 2.4 V \leq EV_{DD0} = EV_{DD1} \leq V_{DD} \leq 5.5 V, Vss = EV_{SS0} = EV_{SS1} = 0 V)

- Notes 1. The value must also be equal to or less than $f_{MCK}/4$.
 - **2.** Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".
- Caution Select the normal input buffer and the N-ch open drain output (V_{DD} tolerance (for the 20- to 52-pin products)/EV_{DD} tolerance (for the 64- to 100-pin products)) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register h (POMh).

(Remarks are listed on the next page.)



(5) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (2/2)

Parameter	Symbol	Symbol Conditions		ions	HS (high-spee	ed main) Mode	Unit
					MIN.	MAX.	
Transfer rate		Transmission	$4.0~V \leq EV_{\text{DD0}} \leq 5.5$			Note 1	bps
			V, $2.7~V \leq V_b \leq 4.0~V$	Theoretical value of the maximum transfer rate		2.6 Note 2	Mbps
				$\begin{array}{l} C_{b}=50 \; pF, \; R_{b}=1.4 \; k\Omega, \; V_{b}=2.7 \\ V \end{array} \label{eq:cb}$			
			$2.7 \ V \leq EV_{\text{DD0}} < 4.0$			Note 3	bps
			V, $2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega, V_b = 2.3$		1.2 Note 4	Mbps
			2.4 V ≤ EV _{DD0} < 3.3	V		Note 5	bps
			V, $1.6~V \leq V_b \leq 2.0~V$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6$ V		0.43 Note 6	Mbps

Notes 1. The smaller maximum transfer rate derived by using fMCK/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V \leq EV _DD0 \leq 5.5 V and 2.7 V \leq V _b \leq 4.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.2}{V_b})\}}{(\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 [\%]$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

- This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.
- 3. The smaller maximum transfer rate derived by using fMCK/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EV_{DD0} < 4.0 V and 2.4 V \leq V_b \leq 2.7 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **4.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 3 above to calculate the maximum transfer rate under conditions of the customer.



Parameter	Symbol	Symbol Conditions		HS (high-speed main) Mode		
			MIN.	MAX.		
SIp setup time	tsik1	$4.0 \ V \leq EV_{\text{DD0}} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$	162		ns	
(to SCKp↑) ^{Note}		$C_b = 30 \text{ pF}, \text{ R}_b = 1.4 \text{ k}\Omega$				
		$2.7 \ V \leq EV_{\text{DD0}} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V,$	354		ns	
		C_b = 30 pF, R_b = 2.7 k Ω				
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \ 1.6 \text{ V} \le \text{V}_{\text{b}} \le 2.0 \text{ V},$	958		ns	
		$C_b = 30 \text{ pF}, \text{ R}_b = 5.5 \text{ k}\Omega$				
SIp hold time	tksi1	$4.0 \ V \le EV_{\text{DD0}} \le 5.5 \ V, \ 2.7 \ V \le V_{\text{b}} \le 4.0 \ V,$	38		ns	
(from SCKp↑) ^{Note}		$C_b = 30 \text{ pF}, \text{ R}_b = 1.4 \text{ k}\Omega$				
		$2.7 \ V \le EV_{\text{DD0}} < 4.0 \ V, \ 2.3 \ V \le V_{\text{b}} \le 2.7 \ V,$	38		ns	
		$C_b = 30 \text{ pF}, \text{ R}_b = 2.7 \text{ k}\Omega$				
		$2.4 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V,$	38		ns	
		$C_b = 30 \text{ pF}, \text{ R}_b = 2.7 \text{ k}\Omega$				
Delay time from SCKp \downarrow to	tkso1	$4.0~V \leq EV_{\text{DD0}} \leq 5.5~V,~2.7~V \leq V_b \leq 4.0~V,$		200	ns	
SOp output ^{Note}		$C_b = 30 \text{ pF}, \text{ R}_b = 1.4 \text{ k}\Omega$				
		$2.7 \ V \le EV_{\text{DD0}} < 4.0 \ V, \ 2.3 \ V \le V_{\text{b}} \le 2.7 \ V,$		390	ns	
		$C_{\rm b}=30~pF,~R_{\rm b}=2.7~k\Omega$				
		$2.4 \ V \le EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \le V_{\text{b}} \le 2.0 \ V,$		966	ns	
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$				

(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (2/3)
 (T₁ = 40 to ±105°C 2.4 V ≤ EVere = EVere ≤ Vere ≤ 5.5 V, Vere = EVere = 6.V)

Note When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (for the 20- to 52-pin products)/EVDD tolerance (for the 64- to 100-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the page after the next page.)



- **Notes 1.** Excludes quantization error ($\pm 1/2$ LSB).
 - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
 - $\label{eq:scalar} \begin{array}{l} \textbf{3. When } AV_{\text{REFP}} < V_{\text{DD}} \text{, the MAX. values are as follows.} \\ \text{Overall error: } Add \pm 1.0 \ \text{LSB} \ \text{to the MAX. value when } AV_{\text{REFP}} = V_{\text{DD}} \text{.} \\ \text{Zero-scale error/Full-scale error: } Add \pm 0.05\%\text{FSR} \ \text{to the MAX. value when } AV_{\text{REFP}} = V_{\text{DD}} \text{.} \\ \text{Integral linearity error/ Differential linearity error: } Add \pm 0.5 \ \text{LSB} \ \text{to the MAX. value when } AV_{\text{REFP}} = V_{\text{DD}} \text{.} \\ \end{array}$
 - 4. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.



3.8 Flash Memory Programming Characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	fclĸ	$2.4~V \leq V_{DD} \leq 5.5~V$	1		32	MHz
Number of code flash rewrites Notes 1,2,3	Cerwr	Retained for 20 years TA = 85° C ^{Note 4}	1,000			Times
Number of data flash rewrites Notes 1,2,3		Retained for 1 years TA = 25°C		1,000,000		
		Retained for 5 years TA = 85° C ^{Note 4}	100,000			
		Retained for 20 years TA = 85°C ^{Note 4}	10,000			

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library.
- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.
- 4. This temperature is the average value at which data are retained.

3.9 Dedicated Flash Memory Programmer Communication (UART)

$(T_{\text{A}} = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \leq \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}, \text{ V}_{\text{SS}} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps



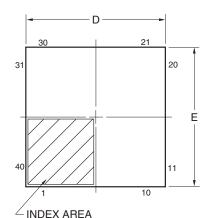
4.7 40-pin Products

R5F100EAANA, R5F100ECANA, R5F100EDANA, R5F100EEANA, R5F100EFANA, R5F100EGANA, R5F100EHANA R5F101EAANA, R5F101ECANA, R5F101EDANA, R5F101EEANA, R5F101EFANA, R5F101EGANA, R5F101EHANA R5F100EADNA, R5F100ECDNA, R5F100EDDNA, R5F100EEDNA, R5F100EFDNA, R5F100EGDNA, R5F100EHDNA

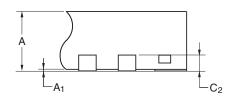
R5F101EADNA, R5F101ECDNA, R5F101EDDNA, R5F101EEDNA, R5F101EFDNA, R5F101EGDNA, R5F101EHDNA

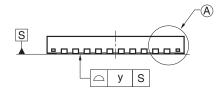
R5F100EAGNA, R5F100ECGNA, R5F100EDGNA, R5F100EEGNA, R5F100EFGNA, R5F100EGGNA, R5F100EHGNA

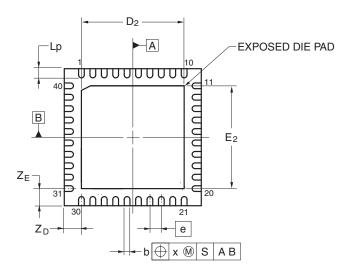
JEITA Package code	RENESAS code	Previous code	MASS (TYP.) [g]
P-HWQFN40-6x6-0.50	PWQN0040KC-A	P40K8-50-4B4-5	0.09



Detail of (A) Part







Referance	Dimens	sion in Mil	limeters
Symbol	Min	Nom	Max
D	5.95	6.00	6.05
E	5.95	6.00	6.05
A			0.80
A ₁	0.00		
b	0.18	0.25	0.30
е		0.50	
Lp	0.30	0.40	0.50
х			0.05
у			0.05
ZD		0.75	—
Z _E		0.75	—
C ₂	0.15	0.20	0.25
D ₂		4.50	
E ₂		4.50	

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4.9 48-pin Products

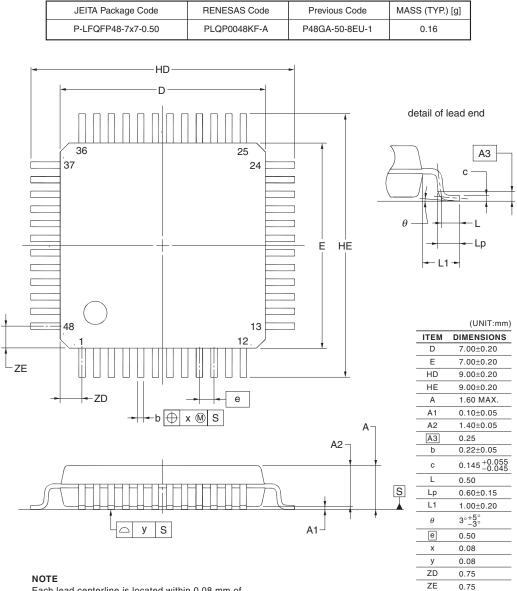
R5F100GAAFB, R5F100GCAFB, R5F100GDAFB, R5F100GEAFB, R5F100GFAFB, R5F100GGAFB, R5F100GHAFB, R5F100GJAFB, R5F100GKAFB, R5F100GLAFB

R5F101GAAFB, R5F101GCAFB, R5F101GDAFB, R5F101GEAFB, R5F101GFAFB, R5F101GGAFB, R5F101GHAFB, R5F101GJAFB, R5F101GKAFB, R5F101GLAFB

R5F100GADFB, R5F100GCDFB, R5F100GDDFB, R5F100GEDFB, R5F100GFDFB, R5F100GGDFB, R5F100GHDFB, R5F100GJDFB, R5F100GKDFB, R5F100GLDFB

R5F101GADFB, R5F101GCDFB, R5F101GDDFB, R5F101GEDFB, R5F101GFDFB, R5F101GGDFB, R5F101GHDFB, R5F101GJDFB, R5F101GKDFB, R5F101GLDFB

R5F100GAGFB, R5F100GCGFB, R5F100GDGFB, R5F100GEGFB, R5F100GFGFB, R5F100GGGFB, R5F100GHGFB, R5F100GJGFB



Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

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			Description
Rev.	Date	Page	Summary
3.00	Aug 02, 2013	118	Modification of table in 2.6.2 Temperature sensor/internal reference voltage characteristics
		118	Modification of table and note in 2.6.3 POR circuit characteristics
		119	Modification of table in 2.6.4 LVD circuit characteristics
		120	Modification of table of LVD Detection Voltage of Interrupt & Reset Mode
		120	Renamed to 2.6.5 Power supply voltage rising slope characteristics
		122	Modification of table, figure, and remark in 2.10 Timing Specs for Switching Flash Memory Programming Modes
		123	Modification of caution 1 and description
		124	Modification of table and remark 3 in Absolute Maximum Ratings ($T_A = 25^{\circ}C$)
		126	Modification of table, note, caution, and remark in 3.2.1 X1, XT1 oscillator characteristics
		126	Modification of table in 3.2.2 On-chip oscillator characteristics
		127	Modification of note 3 in 3.3.1 Pin characteristics (1/5)
		128	Modification of note 3 in 3.3.1 Pin characteristics (2/5)
		133	Modification of notes 1 and 4 in (1) Flash ROM: 16 to 64 KB of 20- to 64-pin products (1/2)
		135	Modification of notes 1, 5, and 6 in (1) Flash ROM: 16 to 64 KB of 20- to 64- pin products (2/2)
		137	Modification of notes 1 and 4 in (2) Flash ROM: 96 to 256 KB of 30- to 100- pin products (1/2)
		139	Modification of notes 1, 5, and 6 in (2) Flash ROM: 96 to 256 KB of 30- to 100-pin products (2/2)
		140	Modification of (3) Peripheral Functions (Common to all products)
		142	Modification of table in 3.4 AC Characteristics
		143	Addition of Minimum Instruction Execution Time during Main System Clock Operation
		143	Modification of figure of AC Timing Test Points
		143	Modification of figure of External System Clock Timing
		145	Modification of figure of AC Timing Test Points
		145	Modification of description, note 1, and caution in (1) During communication at same potential (UART mode)
		146	Modification of description in (2) During communication at same potential (CSI mode)
		147	Modification of description in (3) During communication at same potential (CSI mode)
		149	Modification of table, note 1, and caution in (4) During communication at same potential (simplified I ² C mode)
		151	Modification of table, note 1, and caution in (5) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (1/2)
		152 to 154	Modification of table, notes 2 to 6, caution, and remarks 1 to 4 in (5) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (2/2)
		155	Modification of table in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (1/3)
		156	Modification of table and caution in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (2/3)
		157, 158	Modification of table, caution, and remarks 3 and 4 in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (3/3)
		160, 161	Modification of table and caution in (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode)